

PBL6004D

60 V PNP BISS loadswitch

Rev. 02 — 7 September 2009

Product data sheet

1. Product profile

1.1 General description

PNP low V_{CEsat} Breakthrough In Small Signal (BISS) transistor and NPN Resistor-Equipped Transistor (RET) in a SOT457 (SC-74) small Surface Mounted Device (SMD) plastic package.

1.2 Features

- Low V_{CEsat} (BISS) transistor and resistor-equipped transistor in one package
- Low threshold voltage (< 1 V) compared to MOSFET
- Low drive power required
- Space-saving solution
- Reduction of component count

1.3 Applications

- Supply line switches
- Battery charger switches
- High-side switches for LEDs, drivers and backlights
- Portable equipment

1.4 Quick reference data

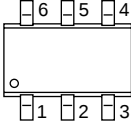
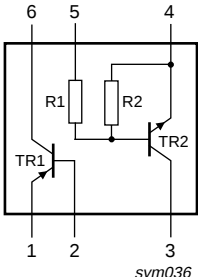
Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
TR1; PNP low V_{CEsat} transistor						
V_{CEO}	collector-emitter voltage	open base	-	-	-60	V
I_C	collector current (DC)		[1] -	-	-1	A
R_{CEsat}	collector-emitter saturation resistance	$I_C = -1$ A; $I_B = -100$ mA	[2] -	255	340	m Ω
TR2; NPN resistor-equipped transistor						
V_{CEO}	collector-emitter voltage	open base	-	-	50	V
I_O	output current (DC)		-	-	100	mA
R1	bias resistor 1 (input)		15.4	22	28.6	k Ω
R2/R1	bias resistor ratio		0.8	1	1.2	

[1] Device mounted on a ceramic Printed-Circuit Board (PCB), Al_2O_3 , standard footprint.

[2] Pulse test: $t_p \leq 300$ μ s; $\delta \leq 0.02$

2. Pinning information

Table 2. Pinning			
Pin	Description	Simplified outline	Symbol
1	emitter TR1		 sym036
2	base TR1		
3	output (collector) TR2		
4	GND (emitter) TR2		
5	input (base) TR2		
6	collector TR1		

3. Ordering information

Table 3. Ordering information			
Type number	Package		
	Name	Description	Version
PBLS6004D	SC-74	plastic surface mounted package; 6 leads	SOT457

4. Marking

Table 4. Marking codes	
Type number	Marking code
PBLS6004D	F4

5. Limiting values

Table 5. Limiting values

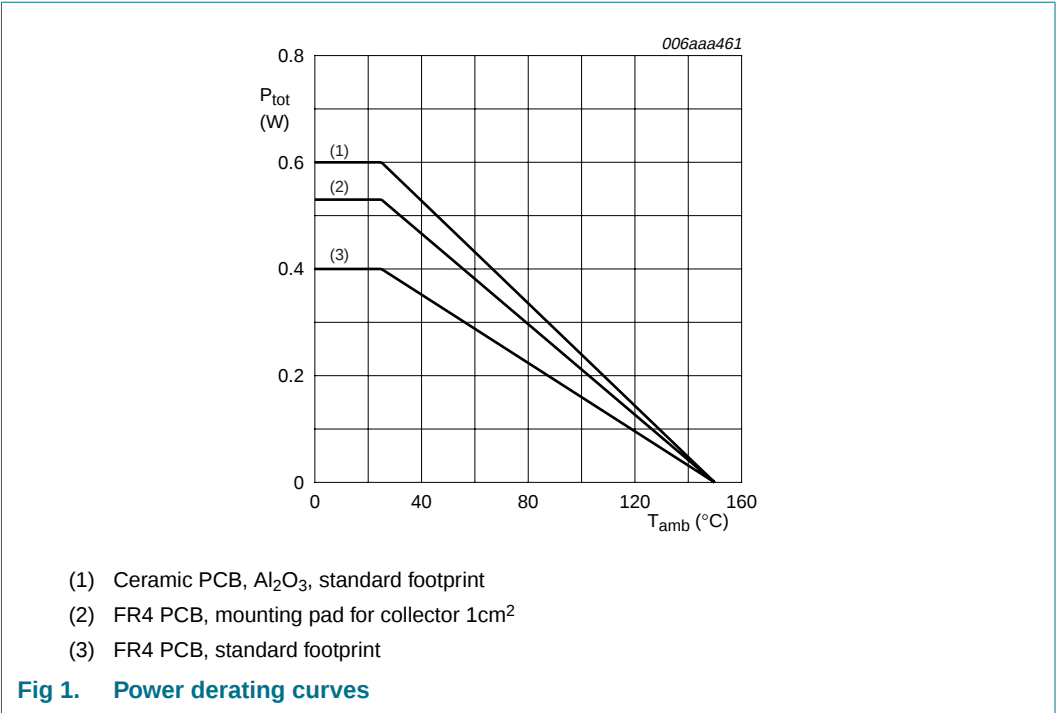
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit	
TR1; PNP low V_{CEsat} transistor						
V_{CBO}	collector-base voltage	open emitter	-	−80	V	
V_{CEO}	collector-emitter voltage	open base	-	−60	V	
V_{EBO}	emitter-base voltage	open collector	-	−5	V	
I_C	collector current (DC)	[1]	-	−700	mA	
		[2]	-	−850	mA	
		[3]	-	−1	A	
I_{CM}	peak collector current	single pulse; $t_p \leq 1$ ms	-	−2	A	
I_B	base current (DC)		-	−300	mA	
I_{BM}	peak base current	single pulse; $t_p \leq 1$ ms	-	−1	A	
P_{tot}	total power dissipation	$T_{amb} \leq 25$ °C	[1]	-	250	mW
			[2]	-	350	mW
			[3]	-	400	mW
TR2; NPN resistor-equipped transistor						
V_{CBO}	collector-base voltage	open emitter	-	50	V	
V_{CEO}	collector-emitter voltage	open base	-	50	V	
V_{EBO}	emitter-base voltage	open collector	-	10	V	
V_I	input voltage					
	positive		-	+40	V	
	negative		-	−10	V	
I_O	output current (DC)		-	100	mA	
I_{CM}	peak collector current		-	100	mA	
P_{tot}	total power dissipation	$T_{amb} \leq 25$ °C	[1]	-	200	mW
			[2]	-	200	mW
			[3]	-	200	mW
Per device						
P_{tot}	total power dissipation	$T_{amb} \leq 25$ °C	[1]	-	400	mW
			[2]	-	530	mW
			[3]	-	600	mW
T_{stg}	storage temperature		−65	+150	°C	
T_j	junction temperature		-	150	°C	
T_{amb}	ambient temperature		−65	+150	°C	

[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1cm².

[3] Device mounted on a ceramic PCB, Al₂O₃, standard footprint.

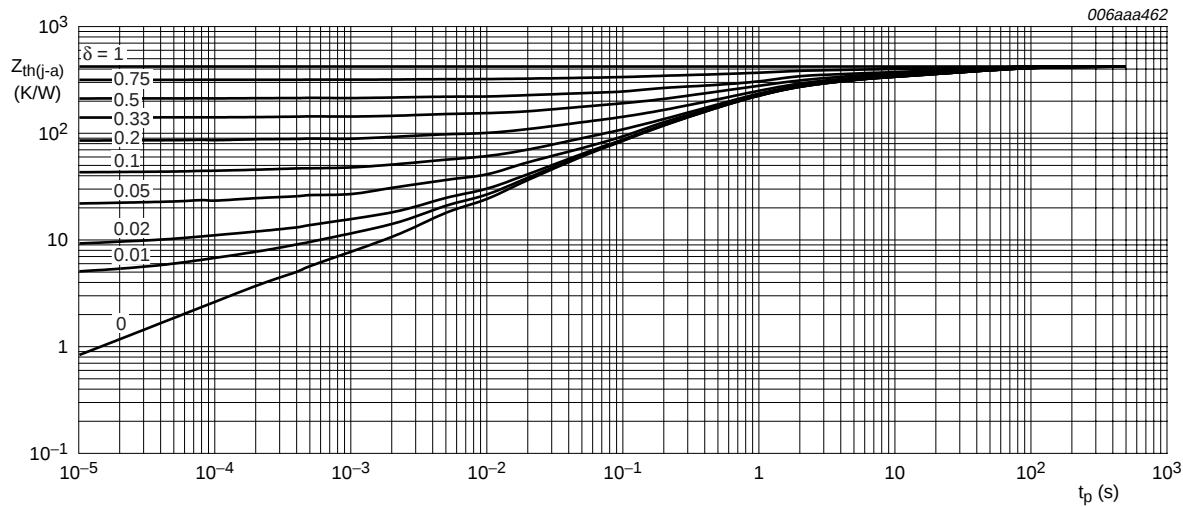


6. Thermal characteristics

Table 6. Thermal characteristics

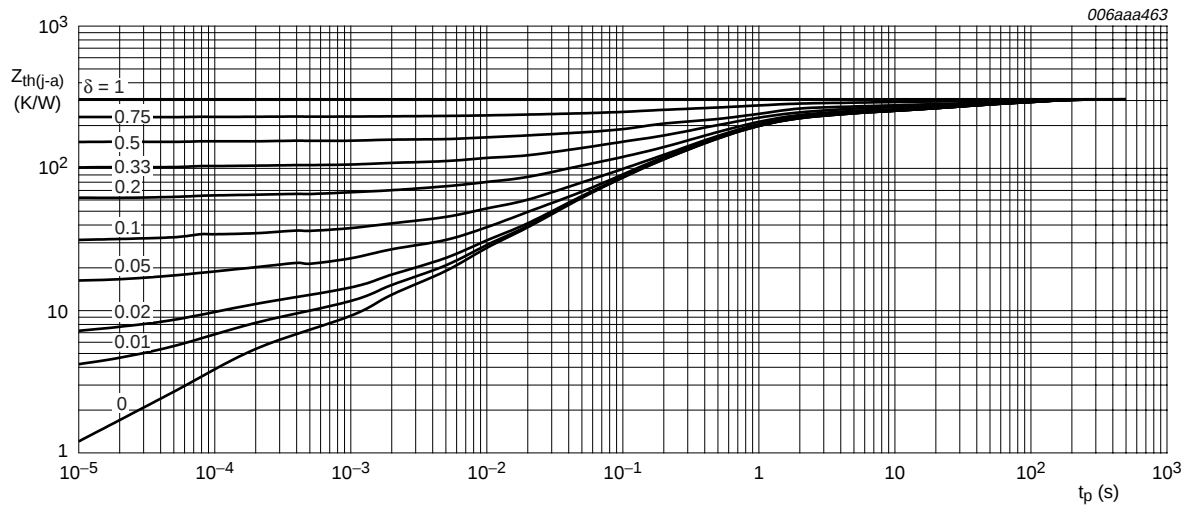
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Per device						
R _{th(j-a)}	thermal resistance from junction to ambient	in free air	[1]	-	312	K/W
			[2]	-	236	K/W
			[3]	-	208	K/W
TR1; PNP low V _{CEsat} transistor						
R _{th(j-sp)}	thermal resistance from junction to solder point		-	-	105	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1cm².
- [3] Device mounted on a ceramic PCB, Al₂O₃, standard footprint.



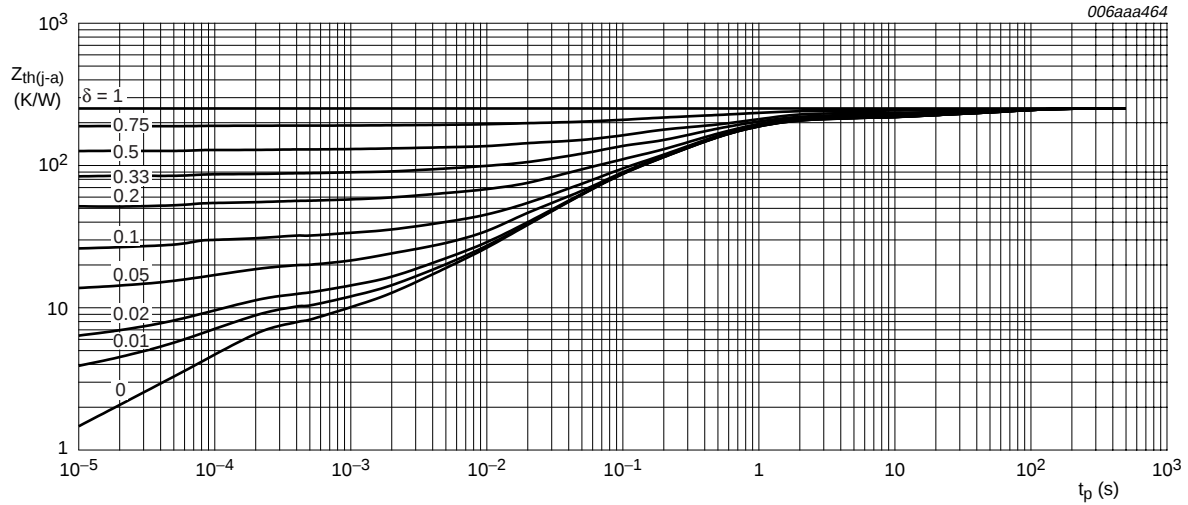
FR4 PCB, standard footprint

Fig 2. TR1 (PNP): Transient thermal impedance from junction to ambient as a function of pulse time; typical values



FR4 PCB, mounting pad for collector 1cm²

Fig 3. TR1 (PNP): Transient thermal impedance from junction to ambient as a function of pulse time; typical values



Ceramic PCB, Al₂O₃, standard footprint

Fig 4. TR1 (PNP): Transient thermal impedance from junction to ambient as a function of pulse time; typical values

7. Characteristics

Table 7. Characteristics

$T_{amb} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

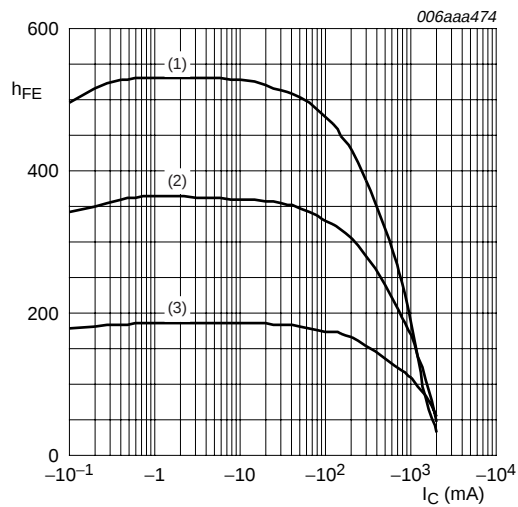
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
TR1; PNP low V_{CEsat} transistor						
I_{CBO}	collector-base cut-off current	$V_{CB} = -60\text{ V}; I_E = 0\text{ A}$	-	-	-100	nA
		$V_{CB} = -60\text{ V}; I_E = 0\text{ A}; T_j = 150\text{ }^{\circ}\text{C}$	-	-	-50	μA
I_{CES}	collector-emitter cut-off current	$V_{CE} = -60\text{ V}; V_{BE} = 0\text{ V}$	-	-	-100	nA
I_{EBO}	emitter-base cut-off current	$V_{EB} = -5\text{ V}; I_C = 0\text{ A}$	-	-	-100	nA
h_{FE}	DC current gain	$V_{CE} = -5\text{ V}; I_C = -1\text{ mA}$	200	350	-	
		$V_{CE} = -5\text{ V}; I_C = -500\text{ mA}$	[1] 150	230	-	
		$V_{CE} = -5\text{ V}; I_C = -1000\text{ mA}$	[1] 100	160	-	
V_{CEsat}	collector-emitter saturation voltage	$I_C = -100\text{ mA}; I_B = -1\text{ mA}$	-	-110	-175	mV
		$I_C = -500\text{ mA}; I_B = -50\text{ mA}$	[1] -	-135	-180	mV
		$I_C = -1000\text{ mA}; I_B = -100\text{ mA}$	[1] -	-255	-340	mV
R_{CEsat}	collector-emitter saturation resistance	$I_C = -1\text{ A}; I_B = -100\text{ mA}$	[1] -	255	340	m Ω
V_{BEsat}	base-emitter saturation voltage	$I_C = -1\text{ A}; I_B = -50\text{ mA}$	[1] -	-0.95	-1.1	V

Table 7. Characteristics ...continued

$T_{amb} = 25^{\circ}\text{C}$ unless otherwise specified

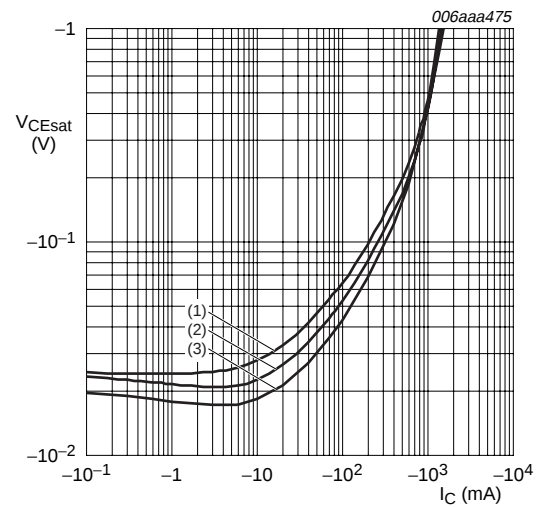
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{BEon}	base-emitter turn-on voltage	$V_{CE} = -5\text{ V}; I_C = -1\text{ A}$	[1] -	-0.82	-0.9	V
t_d	delay time	$I_C = -0.5\text{ A};$ $I_{Bon} = -25\text{ mA};$ $I_{Boff} = 25\text{ mA}$	-	11	-	ns
t_r	rise time		-	30	-	ns
t_{on}	turn-on time		-	41	-	ns
t_s	storage time		-	205	-	ns
t_f	fall time		-	55	-	ns
t_{off}	turn-off time		-	260	-	ns
f_T	transition frequency	$I_C = -50\text{ mA};$ $V_{CE} = -10\text{ V};$ $f = 100\text{ MHz}$	150	185	-	MHz
C_c	collector capacitance	$V_{CB} = -10\text{ V};$ $I_E = i_e = 0\text{ A}; f = 1\text{ MHz}$	-	9	15	pF
TR2; NPN resistor-equipped transistor						
I_{CBO}	collector-base cut-off current	$V_{CB} = 50\text{ V}; I_E = 0\text{ A}$	-	-	100	nA
I_{CEO}	collector-emitter cut-off current	$V_{CE} = 30\text{ V}; I_B = 0\text{ A}$	-	-	1	μA
		$V_{CE} = 30\text{ V}; I_B = 0\text{ A};$ $T_j = 150^{\circ}\text{C}$	-	-	50	μA
I_{EBO}	emitter-base cut-off current	$V_{EB} = 5\text{ V}; I_C = 0\text{ A}$	-	-	180	μA
h_{FE}	DC current gain	$V_{CE} = 5\text{ V}; I_C = 5\text{ mA}$	60	-	-	
V_{CEsat}	collector-emitter saturation voltage	$I_C = 10\text{ mA};$ $I_B = 0.5\text{ mA}$	-	-	150	mV
$V_{I(off)}$	off-state input voltage	$V_{CE} = 5\text{ V}; I_C = 100\text{ }\mu\text{A}$	-	1.1	0.8	V
$V_{I(on)}$	on-state input voltage	$V_{CE} = 0.3\text{ V}; I_C = 5\text{ mA}$	2.5	1.7	-	V
R1	bias resistor 1 (input)		15.4	22	28.6	k Ω
R2/R1	bias resistor ratio		0.8	1	1.2	
C_c	collector capacitance	$V_{CB} = 10\text{ V};$ $I_E = i_e = 0\text{ A}; f = 1\text{ MHz}$	-	-	2.5	pF

[1] Pulse test: $t_p \leq 300\text{ }\mu\text{s}; \delta \leq 0.02$



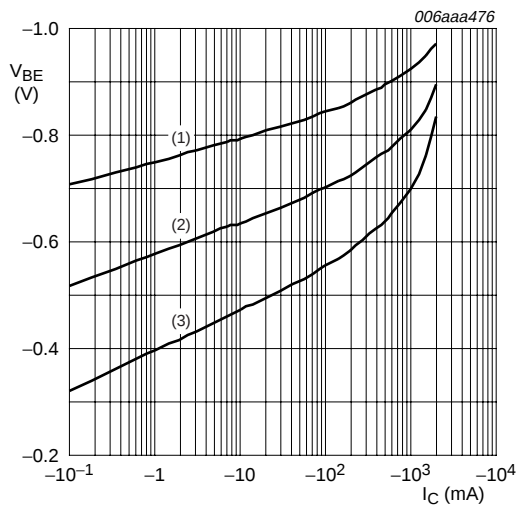
- $V_{CE} = -5 \text{ V}$
- (1) $T_{amb} = 100 \text{ }^{\circ}\text{C}$
 - (2) $T_{amb} = 25 \text{ }^{\circ}\text{C}$
 - (3) $T_{amb} = -55 \text{ }^{\circ}\text{C}$

Fig 5. TR1 (PNP): DC current gain as a function of collector current; typical values



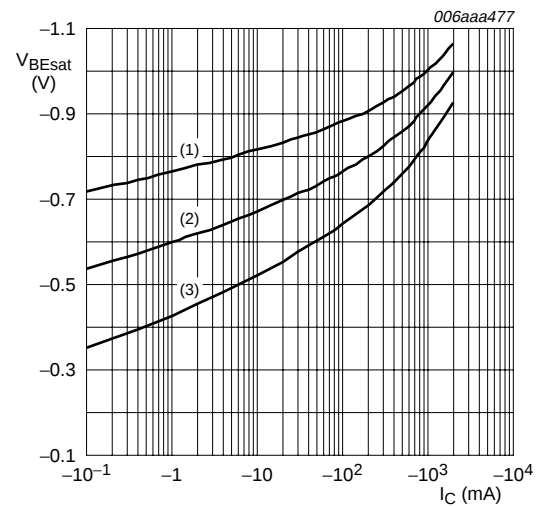
- $I_C/I_B = 20$
- (1) $T_{amb} = 100 \text{ }^{\circ}\text{C}$
 - (2) $T_{amb} = 25 \text{ }^{\circ}\text{C}$
 - (3) $T_{amb} = -55 \text{ }^{\circ}\text{C}$

Fig 6. TR1 (PNP): Collector-emitter saturation voltage as a function of collector current; typical values



- $V_{CE} = -5 \text{ V}$
- (1) $T_{amb} = -55 \text{ }^{\circ}\text{C}$
 - (2) $T_{amb} = 25 \text{ }^{\circ}\text{C}$
 - (3) $T_{amb} = 100 \text{ }^{\circ}\text{C}$

Fig 7. TR1 (PNP): Base-emitter voltage as a function of collector current; typical values



- $I_C/I_B = 20$
- (1) $T_{amb} = -55 \text{ }^{\circ}\text{C}$
 - (2) $T_{amb} = 25 \text{ }^{\circ}\text{C}$
 - (3) $T_{amb} = 100 \text{ }^{\circ}\text{C}$

Fig 8. TR1 (PNP): Base-emitter saturation voltage as a function of collector current; typical values

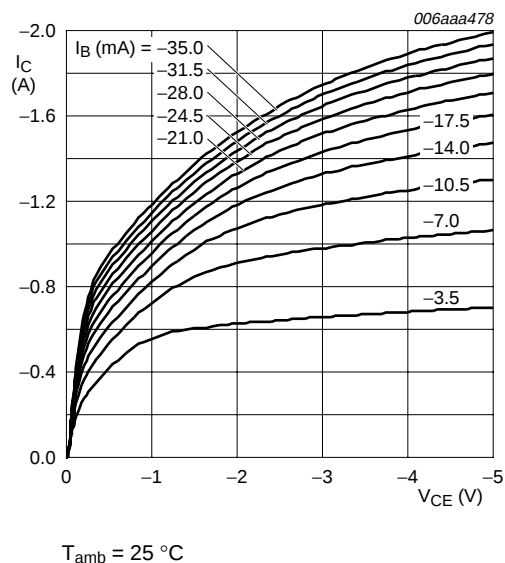


Fig 9. TR1 (PNP): Collector current as a function of collector-emitter voltage; typical values

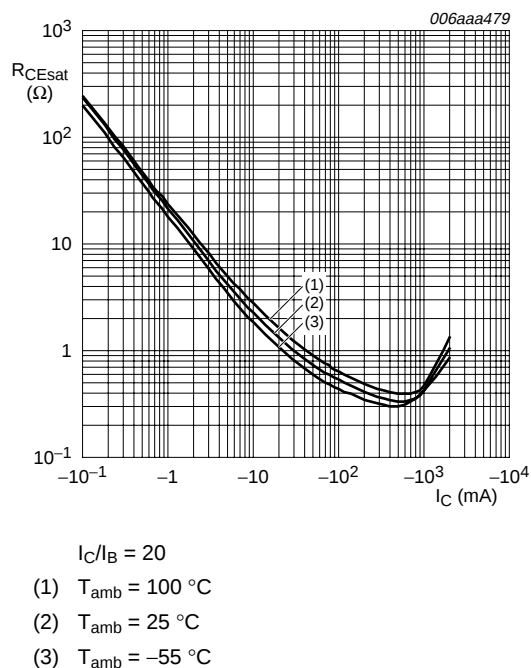


Fig 10. TR1 (PNP): Collector-emitter saturation resistance as a function of collector current; typical values

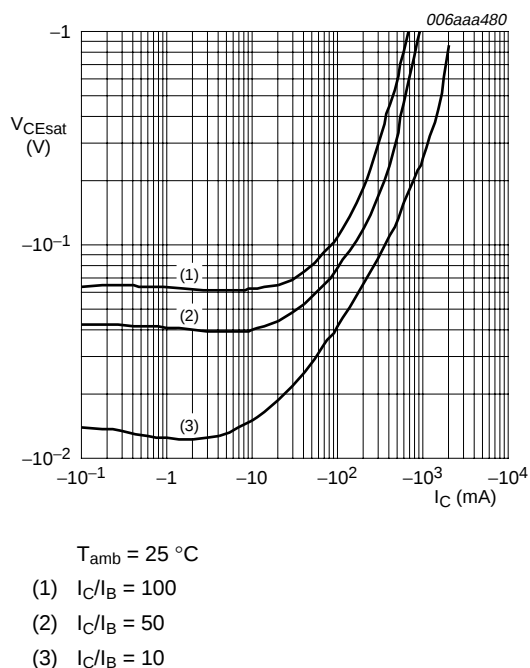


Fig 11. TR1 (PNP): Collector-emitter saturation voltage as a function of collector current; typical values

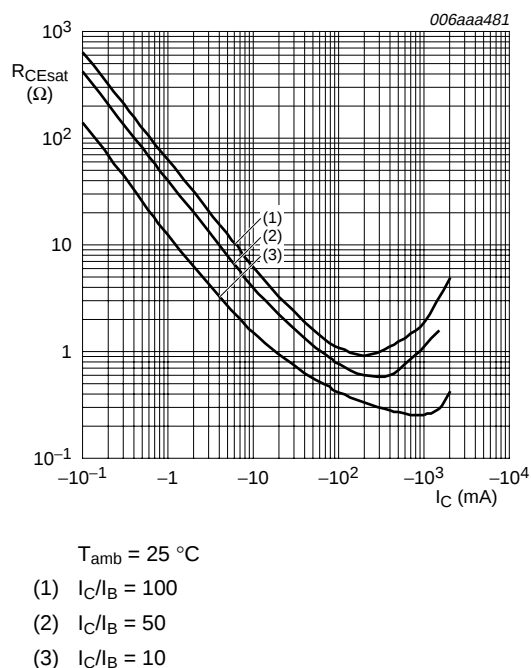
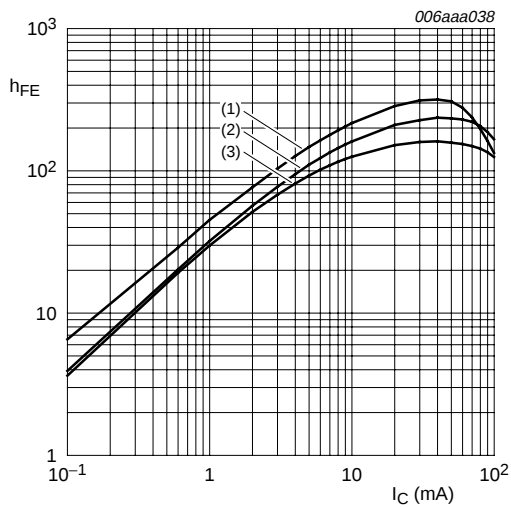
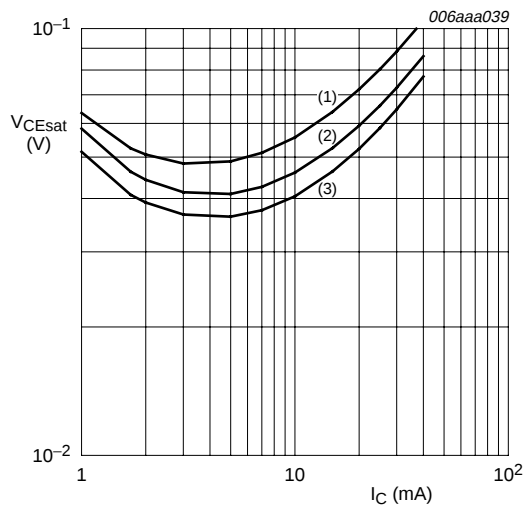


Fig 12. TR1 (PNP): Collector-emitter saturation resistance as a function of collector current; typical values



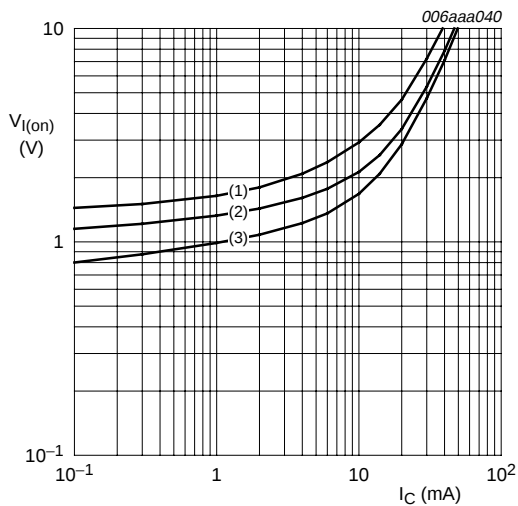
- $V_{CE} = 5$ V
- (1) $T_{amb} = 150$ °C
 - (2) $T_{amb} = 25$ °C
 - (3) $T_{amb} = -40$ °C

Fig 13. TR2 (NPN): DC current gain as a function of collector current; typical values



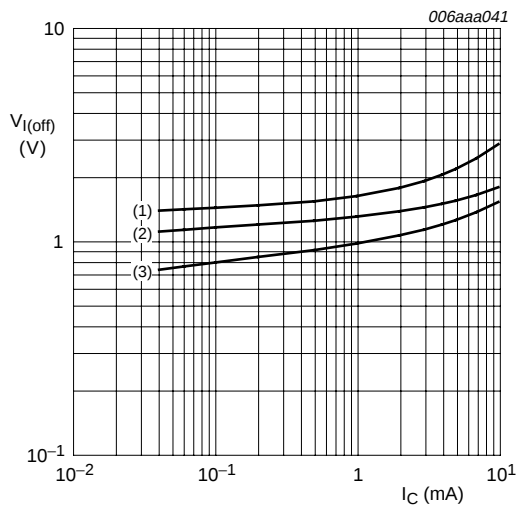
- $I_C/I_B = 20$
- (1) $T_{amb} = 100$ °C
 - (2) $T_{amb} = 25$ °C
 - (3) $T_{amb} = -40$ °C

Fig 14. TR2 (NPN): Collector-emitter saturation voltage as a function of collector current; typical values



- $V_{CE} = 0.3$ V
- (1) $T_{amb} = -40$ °C
 - (2) $T_{amb} = 25$ °C
 - (3) $T_{amb} = 100$ °C

Fig 15. TR2 (NPN): On-state input voltage as a function of collector current; typical values



- $V_{CE} = 5$ V
- (1) $T_{amb} = -40$ °C
 - (2) $T_{amb} = 25$ °C
 - (3) $T_{amb} = 100$ °C

Fig 16. TR2 (NPN): Off-state input voltage as a function of collector current; typical values

8. Test information

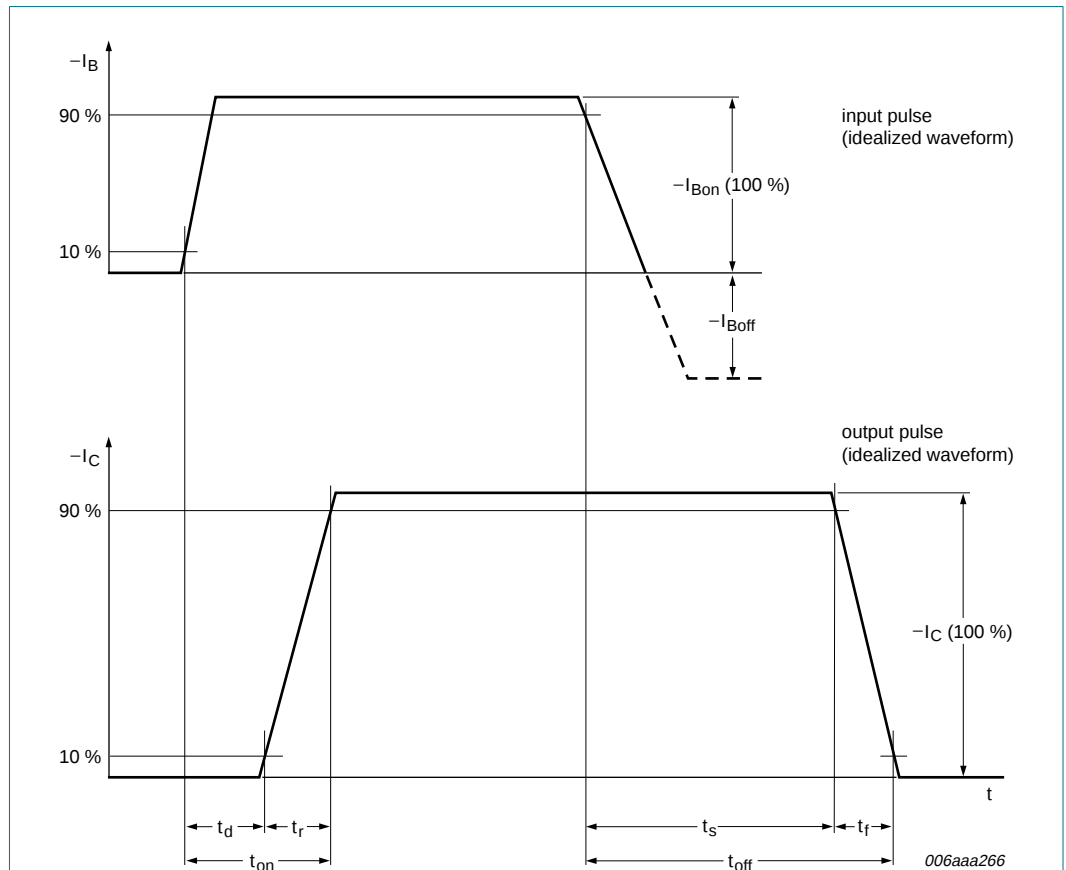
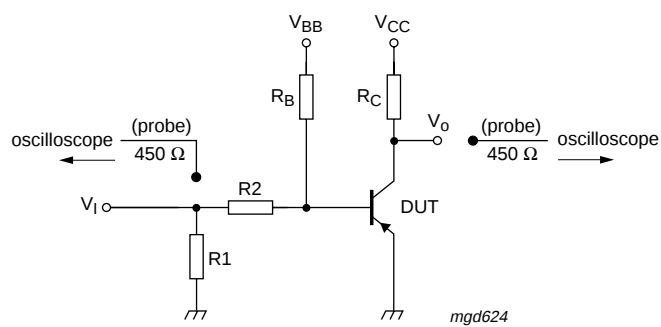


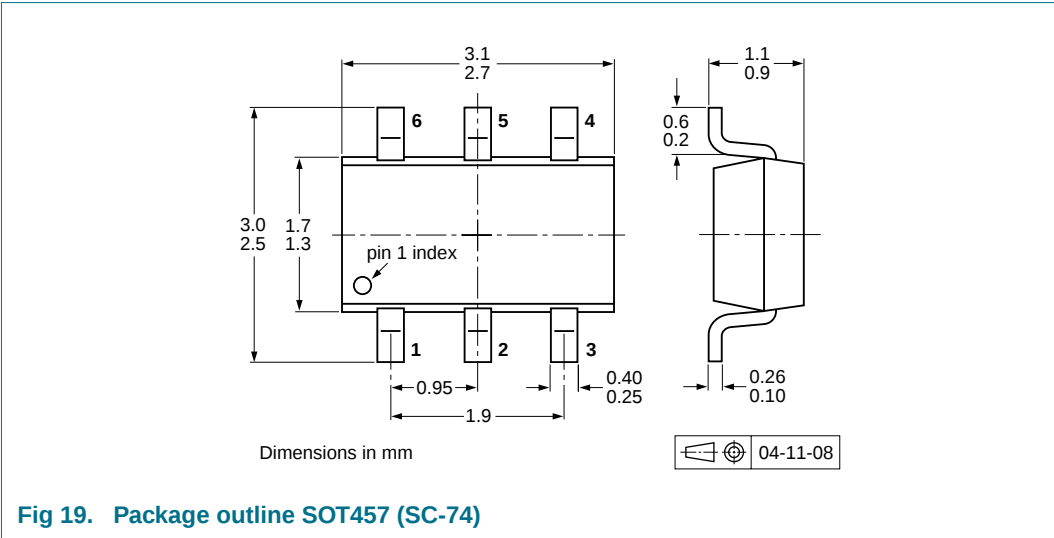
Fig 17. BISS transistor switching time definition



$I_C = -0.5 \text{ A}$; $I_{Bon} = -25 \text{ mA}$; $I_{Boff} = 25 \text{ mA}$; $R_1 = \text{open}$; $R_2 = 100 \text{ } \Omega$; $R_B = 300 \text{ } \Omega$; $R_C = 20 \text{ } \Omega$

Fig 18. Test circuit for switching times

9. Package outline



10. Packing information

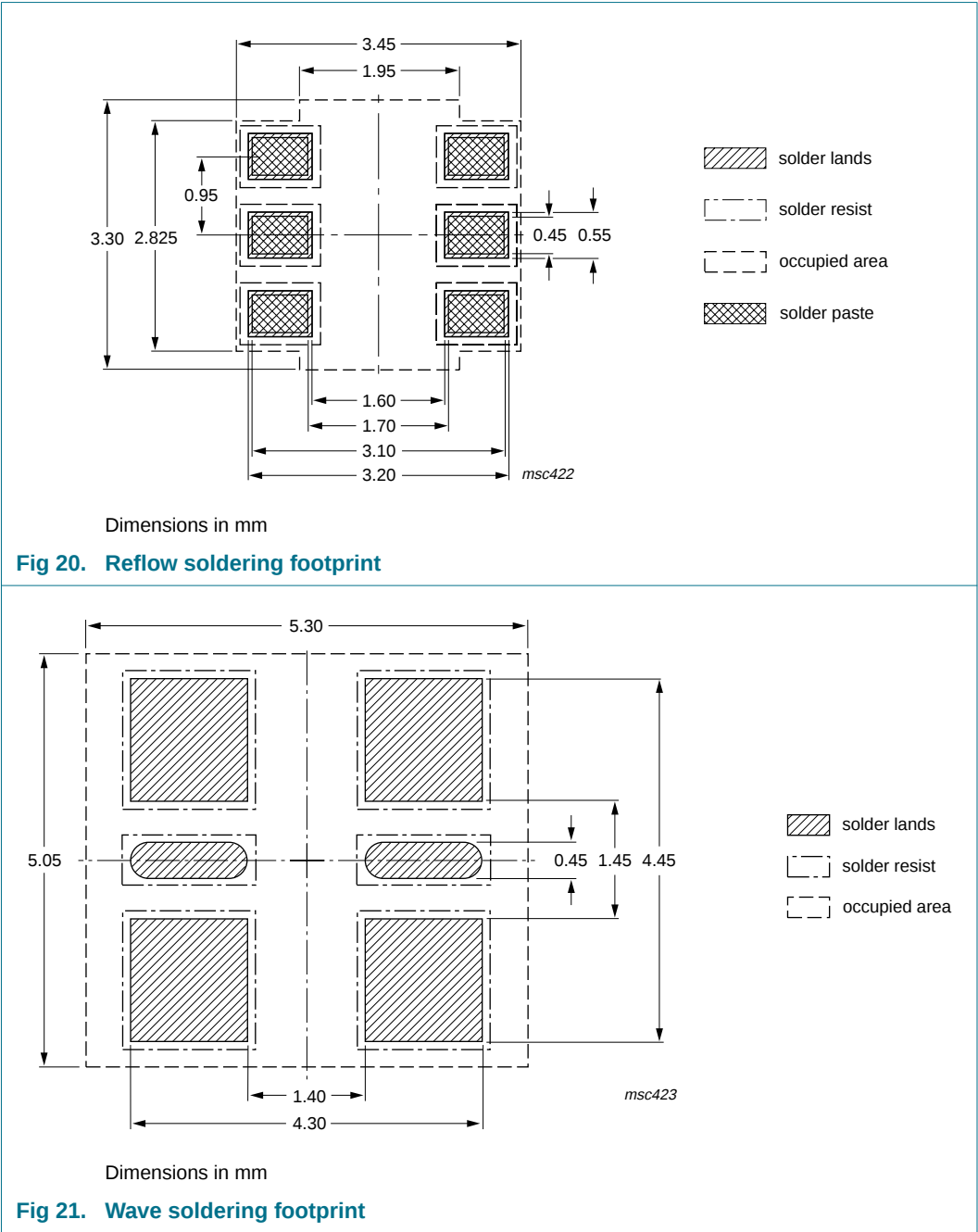
Table 8. Packing methods

 The indicated -xxx are the last three digits of the 12NC ordering code.^[1]

Type number	Package	Description	Packing quantity	
			3000	10000
PBLS6004D	SOT457	4 mm pitch, 8 mm tape and reel; T1 ^[2]	-115	-135
		4 mm pitch, 8 mm tape and reel; T2 ^[3]	-125	-165

- [1] For further information and the availability of packing methods, see [Section 14](#).
- [2] T1: normal taping
- [3] T2: reverse taping

11. Soldering



12. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PBLS6004D_2	20090907	Product data sheet	-	PBLS6004D_1
Modifications:	- This data sheet was changed to reflect the new company name NXP Semiconductors, including new legal definitions and disclaimers. No changes were made to the technical content. Figure 6 “TR1 (PNP): Collector-emitter saturation voltage as a function of collector current; typical values”: V_{CEsat} unit amended from mV to V Figure 21 “Wave soldering footprint”: updated			
PBLS6004D_1	20050623	Product data sheet	-	-

13. Legal information

13.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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13.4 Trademarks

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14. Contact information

For more information, please visit: <http://www.nxp.com>

For sales office addresses, please send an email to: salesaddresses@nxp.com

15. Contents

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